References


Jahangiri, J., and Press, R. (2008, September). Test patterns for ICs that are both secure and have very high coverage. *In AUTOTESTCON, 2008 IEEE* (pp. 92-96). IEEE.


Zhao, H., Xiao, T., and Han, X. (2009, August). The application of boundary-scan technology to FPGA-based experiment system. *In Electronic Measurement and Instruments, 2009. ICEMI ’09. 9th International Conference on* (pp. 622-629). IEEE.